Search Notes

Application/Control No.
10/650,574
Examiner

James D. Stein

Applicant(s)/Patent under Reexamination		
KIM ET AL.		
Art Unit		
2874		

SEARCHED						
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Class	Subclass	Date	Examiner			
385	52,88,90, 97	3/14/2005	JDS 10)			
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
See attached EAST search history	3/14/2005	JDS M	
INSPEC and IEEE databases: waveguide, planar, fiber, substrate, alignement, table, surface, rotation	3/15/2005	JDS 30)	
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